## PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of:

Yoshitaka SASAGO et al.

Appln. No.:

Filed: HEREWITH

For: NONVOLATILE SEMICONDUCTOR MEMORY DEVICE AND

MANUFACTURING METHOD THEREOF

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Applicants wish to make of record the documents cited in prior Application No. 10/166,145 filed June 11, 2002, whether cited by Applicants or by the Patent Office. The documents are listed on the attached Form PTO-1449.

Respectfully submitted,

MWS: 1mb

Miles & Stockbridge P.C. 1751 Pinnacle Drive, Suite 500 McLean, Virginia 22102-3833 (703) 903-9000 November 6, 2003 Rv:

Mitchell W. Shapi

Reg. No. 31,568

		FORM PTO	)-1449		Atty. Docket No.		Ap	Appln. No.	
					XA-9693A				
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